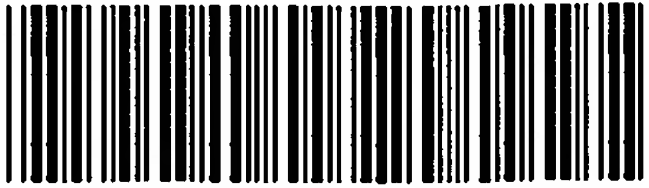


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/647,540	NAPHADE ET AL.	
	Examiner	Art Unit	
	Alex Liew	2624	

SEARCHED			
Class	Subclass	Date	Examiner
382	227	1/17/2007	AL
382	180	1/19/2007	AL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
382/224 limited to text search	1/17/2007	AL
382/181 limited to text search	1/28/2007	AL
382/173 limited to text search	1/19/2007	AL
382/117 limited to text search	1/25/2007	AL